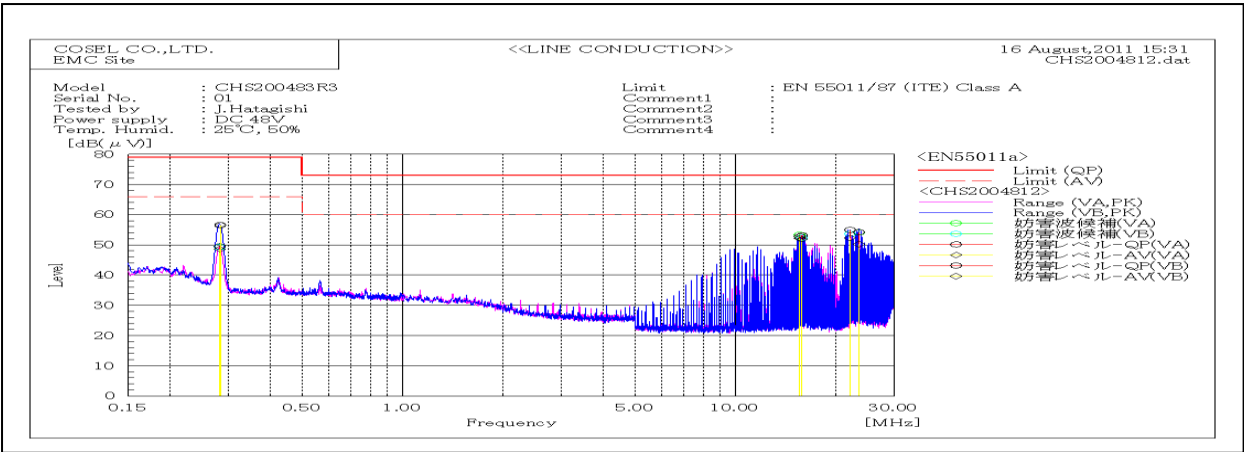
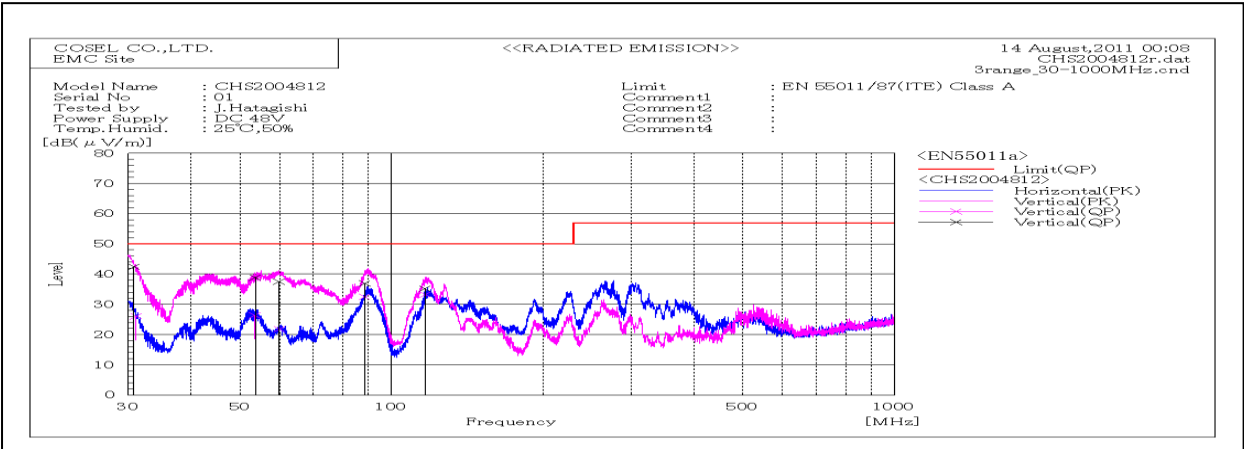


DATA SHEET		Date	16-Aug-11
Model	CHS2004812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi



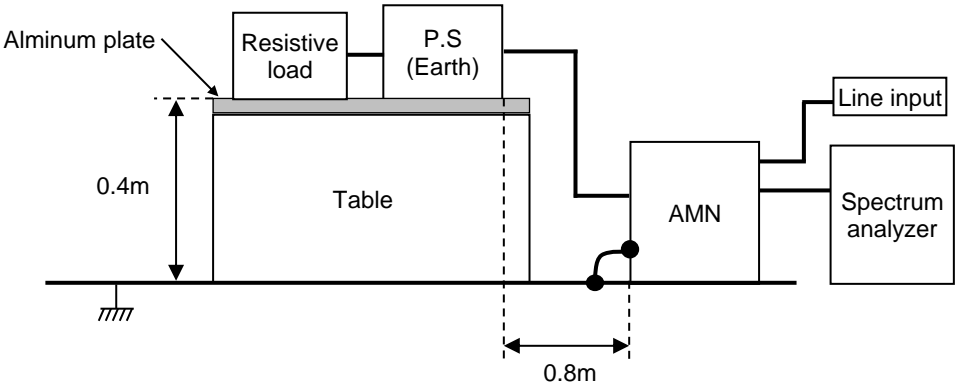
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.28342	VB	46.6	46.6	10	56.6	56.6	79	66	22.4	9.4	Pass
0.28274	VA	39.5	38.6	10	49.5	48.6	79	66	29.5	17.4	Pass
15.5715	VA	42.1	41.5	10.7	52.8	52.2	73	60	20.2	7.8	Pass
15.8489	VB	42.5	41.2	10.7	53.2	51.9	73	60	19.8	8.1	Pass
22.08235	VB	44.1	41.4	10.9	55	52.3	73	60	18	7.7	Pass
23.487	VA	43.2	39.2	11	54.2	50.2	73	60	18.8	9.8	Pass



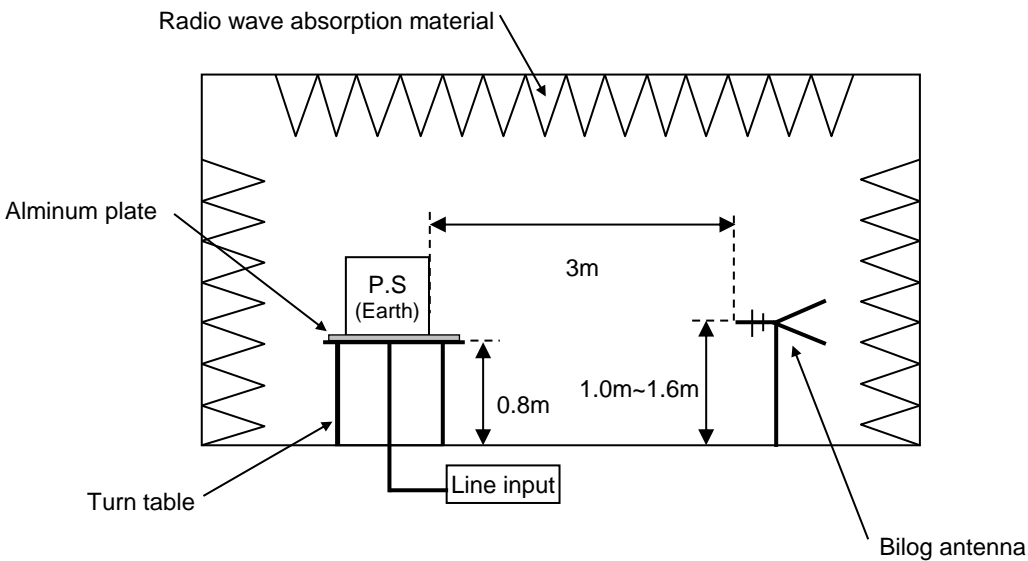
Frequency MHz	Polariz ation	Stabili ty	Readi ng	Space Loss dB	Level	Limit	Margi n	Pass/ Fail	Height cm	Angle deg
			dB(μV)		dB(m W)	dB(mW)				
30.778	V	Stable	56.2	-13.8	42.4	50	7.6	Pass	148	72
53.65	V	Stable	64	-25.2	38.8	50	11.2	Pass	101	290
59.815	V	Stable	63.6	-26.1	37.5	50	12.5	Pass	141	295
88.476	V	Stable	60.1	-23.2	36.9	50	13.1	Pass	136	260
116.7	V	Stable	54.8	-19.6	35.2	50	14.8	Pass	125	321

DATA SHEET		Date	16-Aug-11
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	J.Hatagishi

1. Line conduction



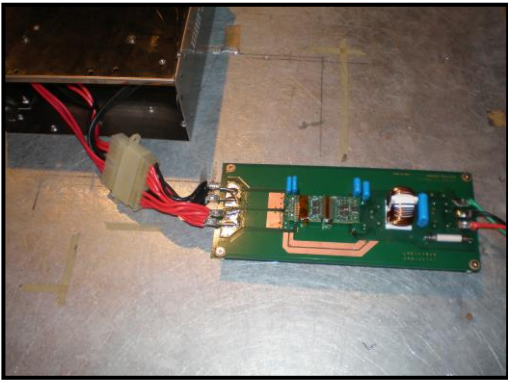
2. Radiated emission



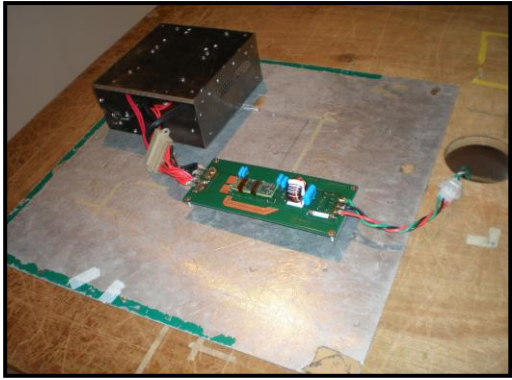
Test : EMI
Model Name : CHS200 Series

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Testing circuitry

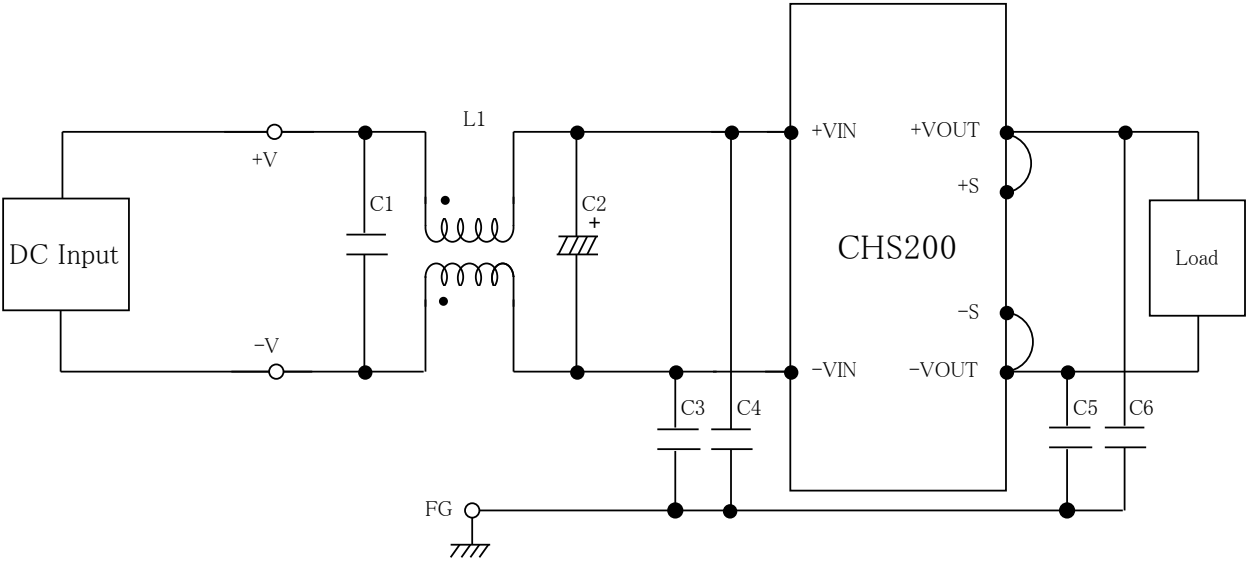


Fig.1 Testing circuitry

- L1 : 1mH SC-10-10J (TOKIN)
- C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
- C2 : 100V 100 μ F PWseries (nichicon)
- C3,C4 : 630V 0.068 μ F FPD22J683J4(NITSUKO)
- C5,C6 : 630V 0.033 μ F FPD22J333J4(NITSUKO)